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applicant's

Hsiao, Tommy C.; Hui, Angela T.; Ogle, Robert B.; Pham, Tuan Du

Plat, Marina V.; Ramsbey, Mark T.; Shen, Lewis

Assignee:

Advanced Micro Devices, Inc.

Title:

Polished Flash Process With Metal Gates And Improved Planarity

Serial No.:

09/430,366

Filing Date:

October 28, 1999

Examiner:

J. Chen

Group Art Unit:

2813

Docket No.:

M-7523 US

Newport Beach, California August 6, 2001

BOX RCE

COMMISSIONER FOR PATENTS

Washington, D. C. 20231

RESPONSE TO OFFICE ACTION

Dear Sir:

This is a response to the April 6, 2001 Office Action. Submitted herewith are also the following documents:

- 1. A petition for a one-month extension of time pursuant to 37 CFR 1.136(a).
- 2. A Request for Continued Examination (RCE) pursuant to 37 CFR 1.114.
- 3. A written statement summarizing a telephonic interview with Examiner Jack

Chen held on August 3, 2001, pursuant to 37 CFR 1.133(b).

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